Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/723,965	TAKEDA, FUJIO	
Examiner	Art Unit	
Danny Nguyen	2836	

			
	SEAR	CHED	
Class	Subclass	Date	Examiner
361	56	7/5/2006	DN
	57		
	58		
			·
	, .		*

INI	ERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	I		

SEAF (INCLUDING S	RCH NOTES EARCH STRATEG	Y)
	DATE	EXMR
East Search	7/5/2006	DN